

**Amendments to the Specification**

Please delete the paragraph on page 2, at lines 5-14, and insert the following therefor:

However, with the large number of light modulation elements, it is impracticable to assume that the SLM will be free from defects. Statistically, there will be at least a few of the tens of millions of light modulation elements of the SLM that are defective. As a result of the multiple imaging process, each defective light modulation element produces N pixel defects on the substrate surface, where N is the number of sections the image is divided into. To limit the number of defects in the transferred image caused by defective light modulation elements, the data can be shifted through the SLM to transfer each image section onto the same portion of the substrate multiple times using different light modulation elements in the SLM, as described in co-pending and commonly assigned U.S. Application for Patent Serial No. [[\_\_\_\_\_]] 10/737,126 (~~Attorney Docket No. 10030571~~).

Please delete the paragraph on page 8, at line 20, though page 9, line 2, and insert the following therefor:

To reduce defects in the transferred image due to light modulation element defects, the data 222 communicated to the SLM 110 during each exposure cycle includes only a portion of the image to enable optical oversampling of the image on the substrate. An example of an optical oversampling technique is described in co-pending and commonly assigned U.S. Applications for Patent Serial Nos.

[[\_\_\_\_\_]] 10/737,126 (~~Attorney Docket No. 10030571~~) and

[[\_\_\_\_\_]] 10/736,090 (~~Attorney Docket No. 10040070~~), which are incorporated by reference herein.